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April 2014

# FDPC8014S

## PowerTrench® Power Clip
## 25V Asymmetric Dual N-Channel MOSFET

### Features

Q1: N-Channel

- Max $r_{DS(on)}$ = 3.8 mΩ at $V_{GS}$ = 10 V, $I_D$ = 20 A
- Max $r_{DS(on)}$ = 4.7 mΩ at $V_{GS}$ = 4.5 V, $I_D$ = 18 A

Q2: N-Channel

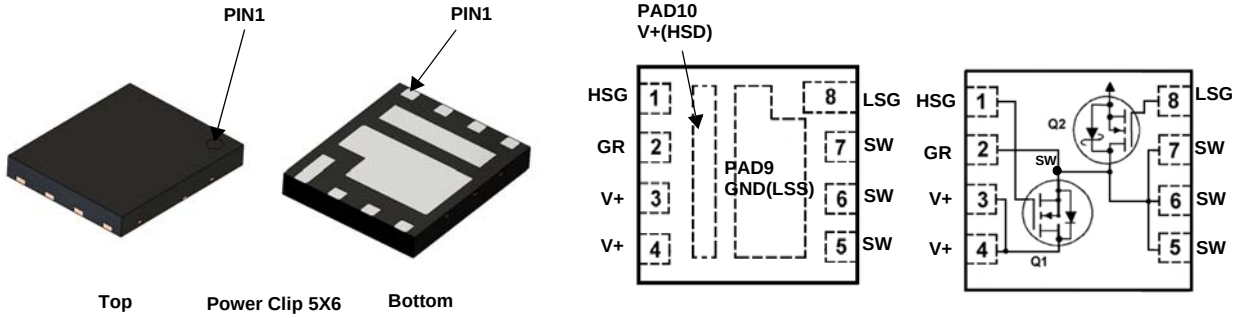
- Max $r_{DS(on)}$ = 1.2 mΩ at $V_{GS}$ = 10 V, $I_D$ = 41 A
- Max $r_{DS(on)}$ = 1.4 mΩ at $V_{GS}$ = 4.5 V, $I_D$ = 37 A
- Low inductance packaging shortens rise/fall times, resulting in lower switching losses
- MOSFET integration enables optimum layout for lower circuit inductance and reduced switch node ringing
- RoHS Compliant

### General Description

This device includes two specialized N-Channel MOSFETs in a dual package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q1) and synchronous SyncFET™ (Q2) have been designed to provide optimal power efficiency.

### Applications

- Computing
- Communications
- General Purpose Point of Load




| Pin | Name | Description | Pin | Name | Description | Pin | Name | Description |
|---|---|---|---|---|---|---|---|---|
| 1 | HSG | High Side Gate | 3,4,10 | V+(HSD) | High Side Drain | 8 | LSG | Low Side Gate |
| 2 | GR | Gate Return | 5,6,7 | SW | Switching Node, Low Side Drain | 9 | GND(LSS) | Low Side Source |

## MOSFET Maximum Ratings $T_A$ = 25 °C unless otherwise noted

| Symbol | Parameter | | Q1 | Q2 | Units |
|---|---|---|---|---|---|
| $V_{DS}$ | Drain to Source Voltage | | 25[Note5] | 25 | V |
| $V_{GS}$ | Gate to Source Voltage | | ±12 | ±12 | V |
| $I_D$ | Drain Current -Continuous | $T_C$ = 25 °C | 60 | 110 | A |
| | -Continuous | $T_A$ = 25 °C | 20[Note1a] | 41[Note1b] | |
| | -Pulsed | $T_A$ = 25 °C (Note 4) | 75 | 160 | |
| $E_{AS}$ | Single Pulse Avalanche Energy | (Note 3) | 73 | 253 | mJ |
| $P_D$ | Power Dissipation for Single Operation | $T_C$ = 25 °C | 21 | 42 | W |
| | Power Dissipation for Single Operation | $T_A$ = 25 °C | 2.1[Note1a] | 2.3 [Note1b] | |
| $T_J$, $T_{STG}$ | Operating and Storage Junction Temperature Range | | -55 to +150 | | °C |

### Thermal Characteristics

| | | | | |
|---|---|---|---|---|
| $R_{\theta JC}$ | Thermal Resistance, Junction to Case | 6.0 | 3.0 | °C/W |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient | 60[Note1a] | 55[Note1b] | |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient | 130[Note1c] | 120[Note1d] | |

## Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|---|---|---|---|---|---|
| 05OD/16OD | FDPC8014S | Power Clip 56 | 13 ” | 12 mm | 3000 units |

## Electrical Characteristics $T_J$ = 25 °C unless otherwise noted

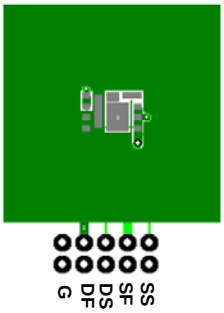
| Symbol | Parameter | Test Conditions | Type | Min | Typ | Max | Units |
|---|---|---|---|---|---|---|---|
| **Off Characteristics** | | | | | | | |
| $BV_{DSS}$ | Drain to Source Breakdown Voltage | $I_D$ = 250 μA, $V_{GS}$ = 0 V<br>$I_D$ = 1 mA, $V_{GS}$ = 0 V | Q1<br>Q2 | 25<br>25 | | | V |
| $\frac{\Delta BV_{DSS}}{\Delta T_J}$ | Breakdown Voltage Temperature Coefficient | $I_D$ = 250 μA, referenced to 25 °C<br>$I_D$ = 10 mA, referenced to 25 °C | Q1<br>Q2 | | 24<br>24 | | mV/°C |
| $I_{DSS}$ | Zero Gate Voltage Drain Current | $V_{DS}$ = 20 V, $V_{GS}$ = 0 V<br>$V_{DS}$ = 20 V, $V_{GS}$ = 0 V | Q1<br>Q2 | | | 1<br>500 | μA<br>μA |
| $I_{GSS}$ | Gate to Source Leakage Current, Forward | $V_{GS}$ = 12 V/-8 V, $V_{DS}$= 0 V<br>$V_{GS}$ = 12 V/-8 V, $V_{DS}$= 0 V | Q1<br>Q2 | | | ±100<br>±100 | nA<br>nA |
| **On Characteristics** | | | | | | | |
| $V_{GS(th)}$ | Gate to Source Threshold Voltage | $V_{GS}$ = $V_{DS}$, $I_D$ = 250 μA<br>$V_{GS}$ = $V_{DS}$, $I_D$ = 1 mA | Q1<br>Q2 | 0.8<br>1.1 | 1.3<br>1.4 | 2.5<br>2.5 | V |
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate to Source Threshold Voltage Temperature Coefficient | $I_D$ = 250 μA, referenced to 25 °C<br>$I_D$ = 10 mA, referenced to 25 °C | Q1<br>Q2 | | -4<br>-3 | | mV/°C |
| $r_{DS(on)}$ | Drain to Source On Resistance | $V_{GS}$ = 10V, $I_D$ = 20 A<br>$V_{GS}$ = 4.5 V, $I_D$ = 18 A<br>$V_{GS}$ = 10 V, $I_D$ = 20 A,$T_J$ =125 °C | Q1 | | 2.8<br>3.4<br>3.9 | 3.8<br>4.7<br>5.3 | mΩ |
| | | $V_{GS}$ = 10V, $I_D$ = 41 A<br>$V_{GS}$ = 4.5 V, $I_D$ = 37 A<br>$V_{GS}$ = 10 V, $I_D$ = 41 A ,$T_J$ =125 °C | Q2 | | 0.9<br>1.0<br>1.1 | 1.2<br>1.4<br>1.5 | |
| $g_{FS}$ | Forward Transconductance | $V_{DS}$ = 5 V, $I_D$ = 20 A<br>$V_{DS}$ = 5 V, $I_D$ = 41 A | Q1<br>Q2 | | 182<br>315 | | S |
| **Dynamic Characteristics** | | | | | | | |
| $C_{iss}$ | Input Capacitance | Q1:<br>$V_{DS}$ = 13 V, $V_{GS}$ = 0 V, f = 1 MHZ<br>Q2:<br>$V_{DS}$ = 13 V, $V_{GS}$ = 0 V, f = 1 MHZ | Q1<br>Q2 | | 1695<br>6580 | 2375<br>9870 | pF |
| $C_{oss}$ | Output Capacitance | | Q1<br>Q2 | | 495<br>1720 | 710<br>2580 | pF |
| $C_{rss}$ | Reverse Transfer Capacitance | | Q1<br>Q2 | | 54<br>204 | 100<br>370 | pF |
| $R_g$ | Gate Resistance | | Q1<br>Q2 | 0.1<br>0.1 | 0.4<br>0.4 | 1.2<br>1.2 | Ω |
| **Switching Characteristics** | | | | | | | |
| $t_{d(on)}$ | Turn-On Delay Time | Q1:<br>$V_{DD}$ = 13 V, $I_D$ = 20 A, $R_{GEN}$ = 6 Ω<br>Q2:<br>$V_{DD}$ = 13 V, $I_D$ = 41 A, $R_{GEN}$ = 6 Ω | Q1<br>Q2 | | 8<br>16 | 16<br>28 | ns |
| $t_r$ | Rise Time | | Q1<br>Q2 | | 2<br>6 | 10<br>11 | ns |
| $t_{d(off)}$ | Turn-Off Delay Time | | Q1<br>Q2 | | 24<br>47 | 38<br>75 | ns |
| $t_f$ | Fall Time | | Q1<br>Q2 | | 2<br>4 | 10<br>10 | ns |
| $Q_g$ | Total Gate Charge | $V_{GS}$ = 0 V to 10 V<br>Q1<br>$V_{DD}$ = 13 V, $I_D$ = 20 A<br>Q2<br>$V_{DD}$ = 13 V, $I_D$ = 41 A | Q1<br>Q2 | | 25<br>93 | 35<br>130 | nC |
| $Q_g$ | Total Gate Charge | $V_{GS}$ = 0 V to 4.5 V | Q1<br>Q2 | | 11<br>43 | 16<br>60 | nC |
| $Q_{gs}$ | Gate to Source Gate Charge | | Q1<br>Q2 | | 3.4<br>13 | | nC |
| $Q_{gd}$ | Gate to Drain “Miller” Charge | | Q1<br>Q2 | | 2.2<br>8.5 | | nC |

## Electrical Characteristics $T_J$ = 25 °C unless otherwise noted

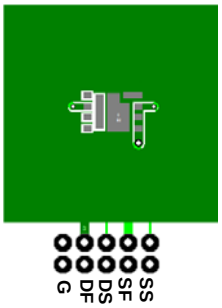
| Symbol | Parameter | Test Conditions | Type | Min | Typ | Max | Units |
|---|---|---|---|---|---|---|---|
| **Drain-Source Diode Characteristics** | | | | | | | |
| $V_{SD}$ | Source to Drain Diode Forward Voltage | $V_{GS}$ = 0 V, $I_S$ = 20 A (Note 2)<br>$V_{GS}$ = 0 V, $I_S$ = 41 A (Note 2) | Q1<br>Q2 | | 0.8<br>0.8 | 1.2<br>1.2 | V |
| $I_S$ | Diode continuous forward current | $T_C$ = 25 °C | Q1<br>Q2 | | 60<br>110 | | A |
| $I_{S,Pulse}$ | Diode pulse current | | Q1<br>Q2 | | 75<br>160 | | A |
| $t_{rr}$ | Reverse Recovery Time | Q1<br>$I_F$ = 20 A, di/dt = 100 A/µs | Q1<br>Q2 | | 25<br>36 | 40<br>58 | ns |
| $Q_{rr}$ | Reverse Recovery Charge | Q2<br>$I_F$ = 41 A, di/dt = 300 A/µs | Q1<br>Q2 | | 10<br>47 | 20<br>75 | nC |

Notes:

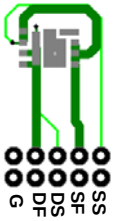
1.$R_{\theta JA}$ is determined with the device mounted on a 1 $in^2$ pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



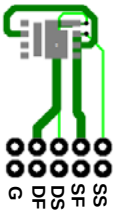

a. 60 °C/W when mounted on a 1 $in^2$ pad of 2 oz copper




b. 55 °C/W when mounted on a 1 $in^2$ pad of 2 oz copper




c. 130 °C/W when mounted on a minimum pad of 2 oz copper




d. 120 °C/W when mounted on a minimum pad of 2 oz copper

2 Pulse Test: Pulse Width < 300 µs, Duty cycle < 2.0%.

3. Q1 :$E_{AS}$ of 73 mJ is based on starting $T_J$ = 25 °C; N-ch: L = 3 mH, $I_{AS}$ = 7 A, $V_{DD}$ = 30 V, $V_{GS}$ = 10 V. 100% test at L= 0.1 mH, $I_{AS}$ = 24 A.
Q2: $E_{AS}$ of 253 mJ is based on starting $T_J$ = 25 °C; N-ch: L = 3 mH, $I_{AS}$ = 13 A, $V_{DD}$ = 25 V, $V_{GS}$ = 10 V. 100% test at L= 0.1 mH, $I_{AS}$ = 43 A.

4. Pulsed Id limited by junction temperature,td<=10 us. Please refer to SOA curve for more details.

5. The continuous $V_{DS}$ rating is 25 V; However, a pulse of 30 V peak voltage for no longer than 100 ns duration at 600 KHz frequency can be applied.

## Typical Characteristics (Q1 N-Channel) $T_J$ = 25°C unless otherwise noted

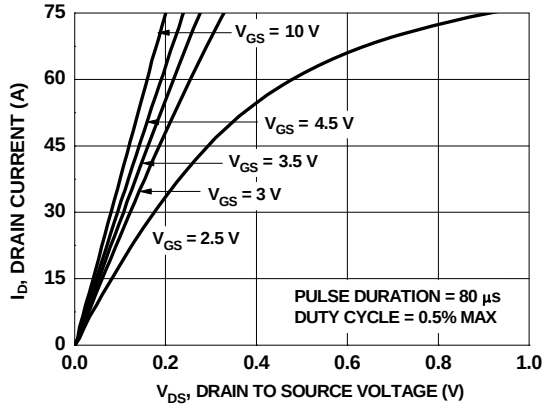



**Figure 1. On Region Characteristics**

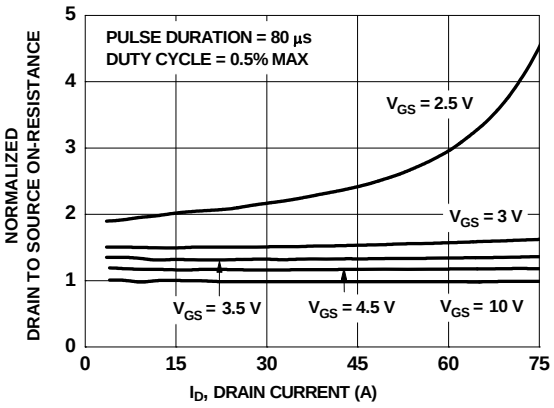



**Figure 2. Normalized On-Resistance vs. Drain Current and Gate Voltage**

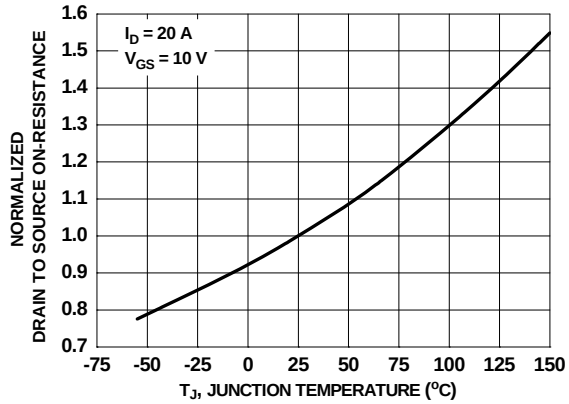



**Figure 3. Normalized On Resistance vs. Junction Temperature**

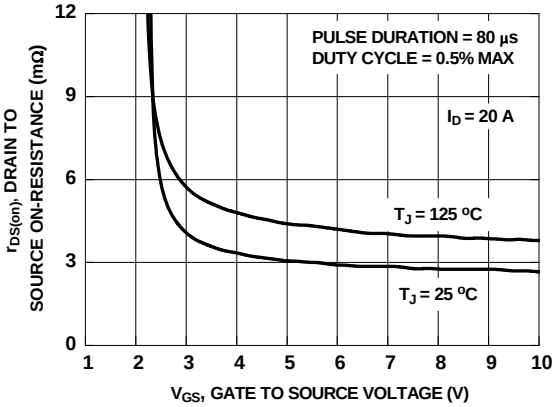



**Figure 4. On-Resistance vs. Gate to Source Voltage**

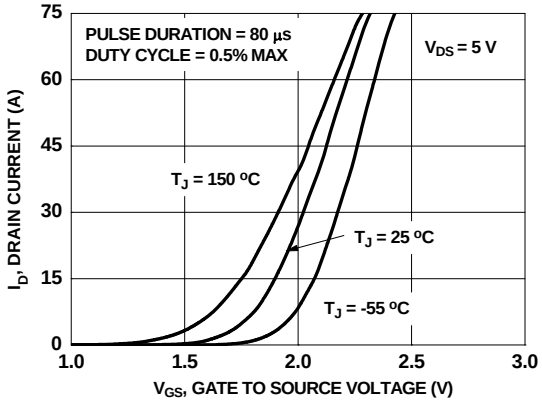



**Figure 5. Transfer Characteristics**

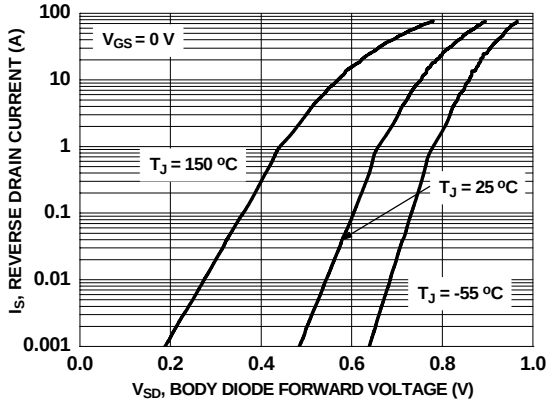



**Figure 6. Source to Drain Diode Forward Voltage vs. Source Current**

## Typical Characteristics (Q1 N-Channel) $T_J$ = 25°C unless otherwise noted

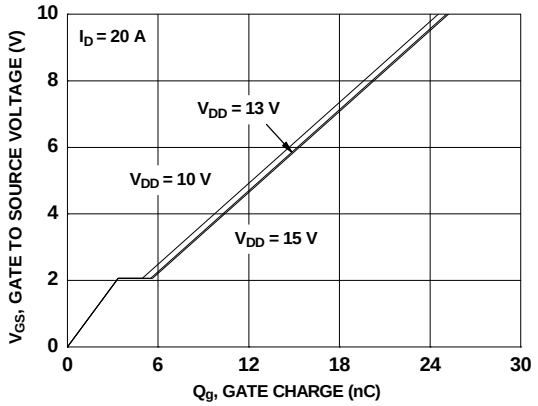



**Figure 7. Gate Charge Characteristics**

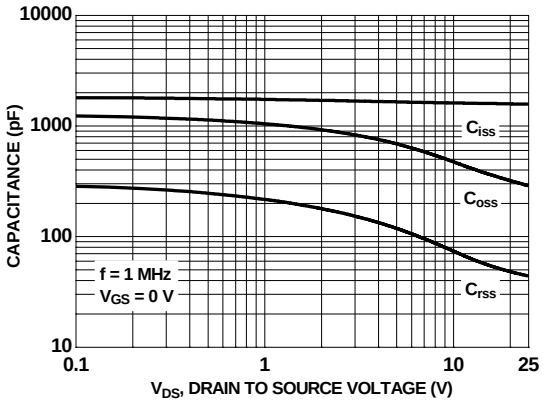



**Figure 8. Capacitance vs. Drain to Source Voltage**

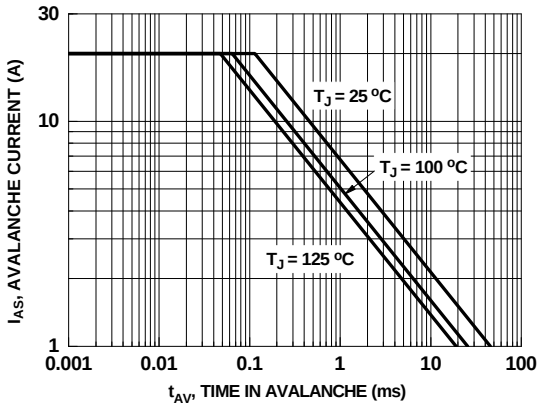



**Figure 9. Unclamped Inductive Switching Capability**

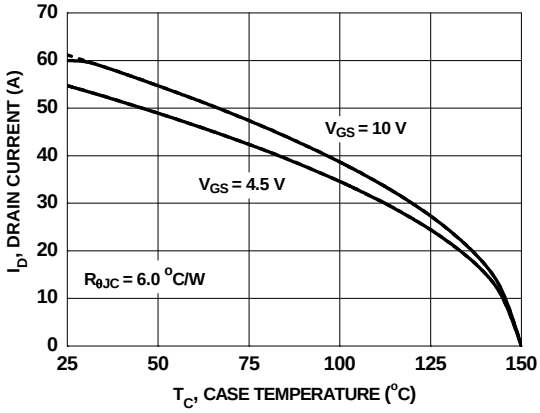



**Figure 10. Maximum Continuous Drain Current vs. Case Temperature**

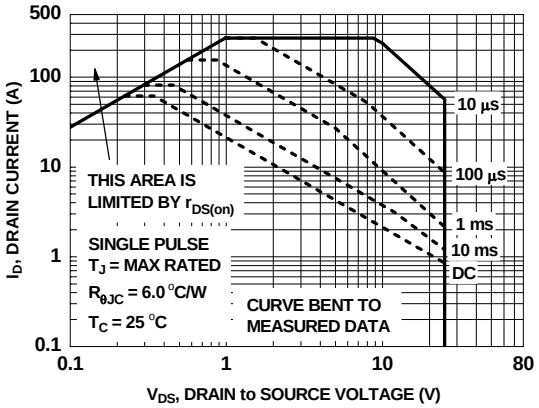



**Figure 11. Forward Bias Safe Operating Area**

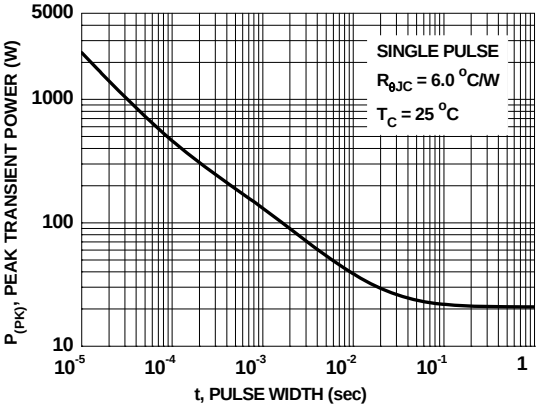



**Figure 12. Single Pulse Maximum Power Dissipation**

## Typical Characteristics (Q1 N-Channel) $T_J$ = 25°C unless otherwise noted

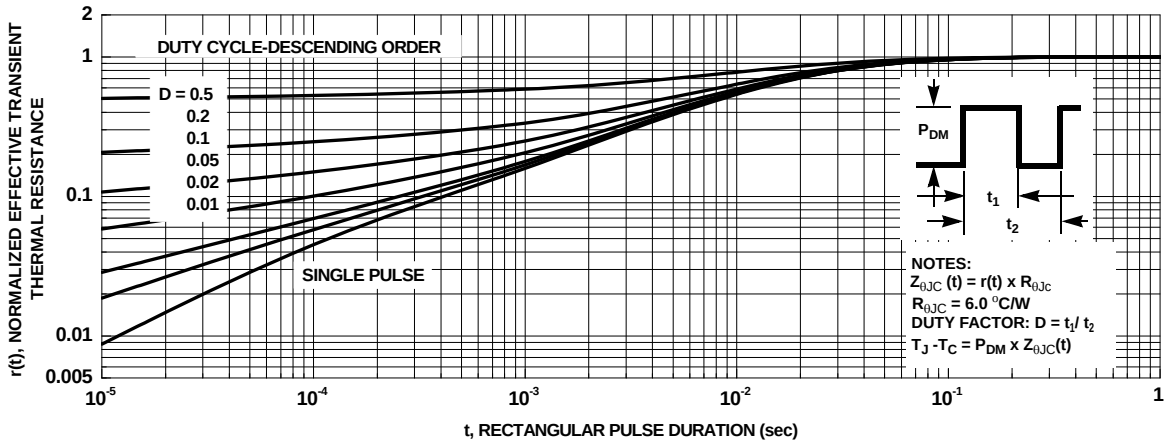



**Figure 13. Junction-to-Case Transient Thermal Response Curve**

## Typical Characteristics (Q2 N-Channel) $T_J$ = 25 °C unless otherwise noted

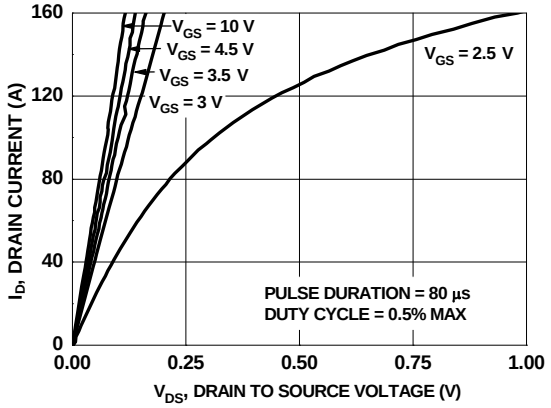



**Figure 14. On- Region Characteristics**

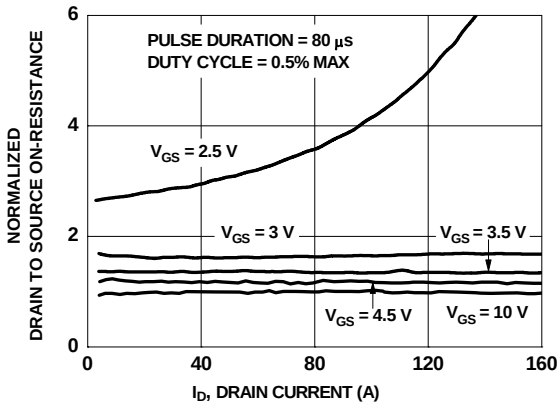



**Figure 15. Normalized on-Resistance vs. Drain Current and Gate Voltage**

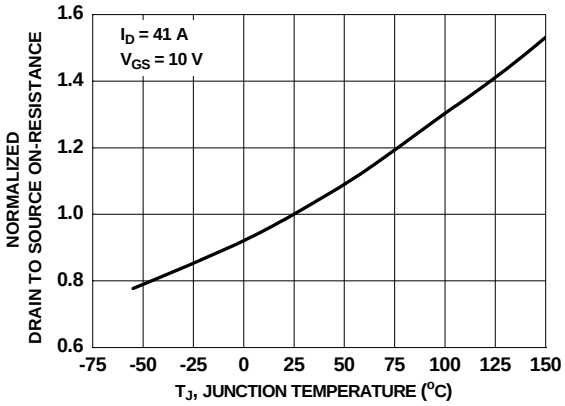



**Figure 16. Normalized On-Resistance vs. Junction Temperature**

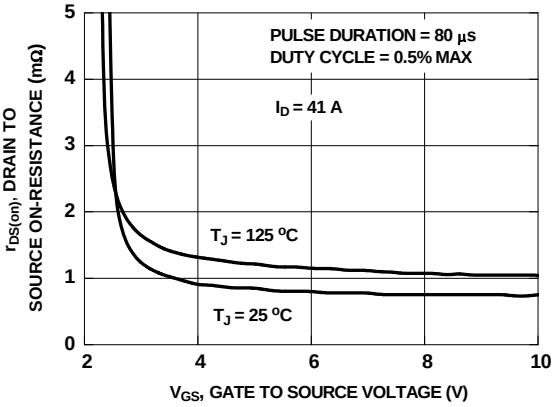



**Figure 17. On-Resistance vs. Gate to Source Voltage**

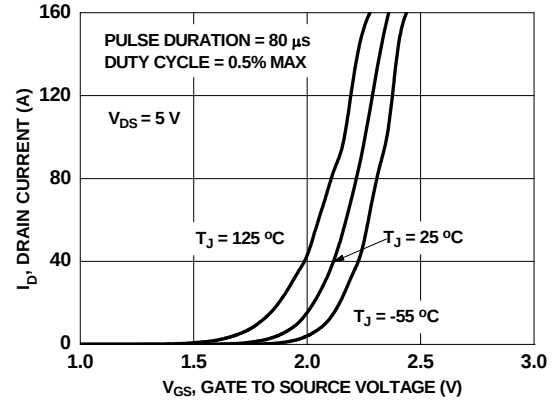



**Figure 18. Transfer Characteristics**

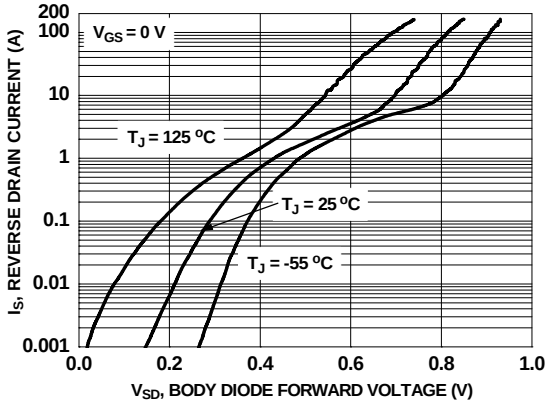



**Figure 19. Source to Drain Diode Forward Voltage vs. Source Current**

## Typical Characteristics (Q2 N-Channel) $T_J$ = 25°C unless otherwise noted

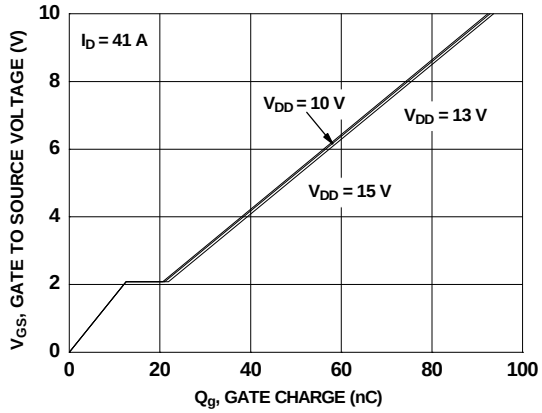



**Figure 20. Gate Charge Characteristics**

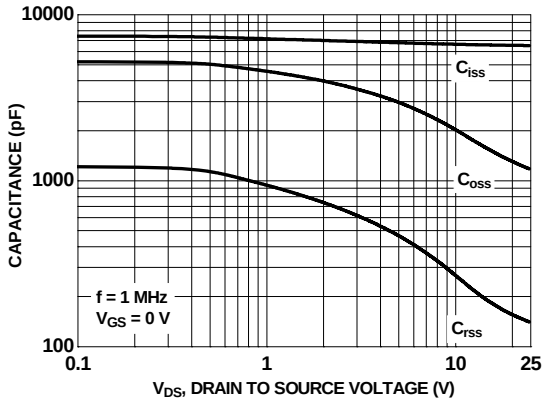



**Figure 21. Capacitance vs. Drain to Source Voltage**

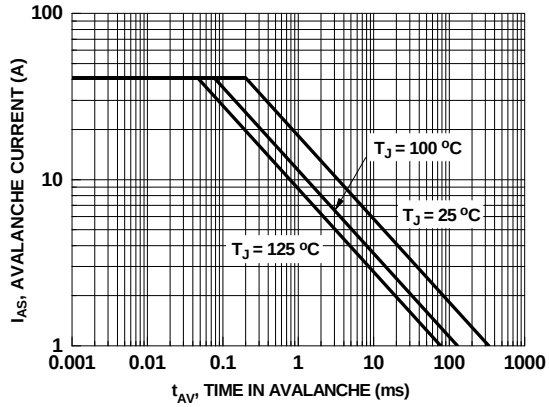



**Figure 22. Unclamped Inductive Switching Capability**

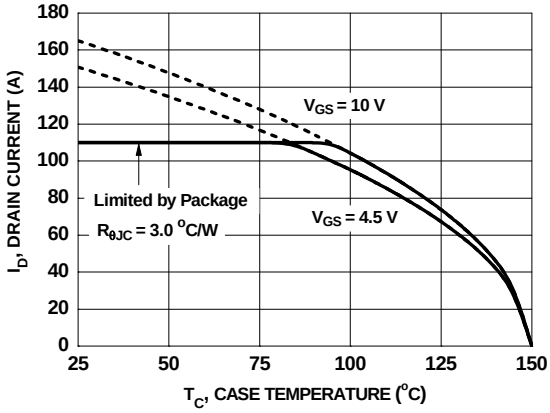



**Figure 23. Maximum Continuous Drain Current vs. Case Temperature**

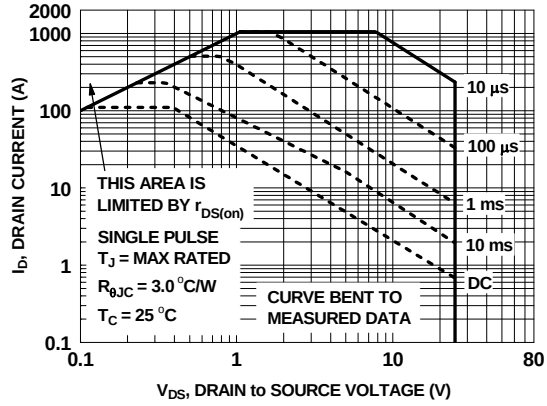



**Figure 24. Forward Bias Safe Operating Area**

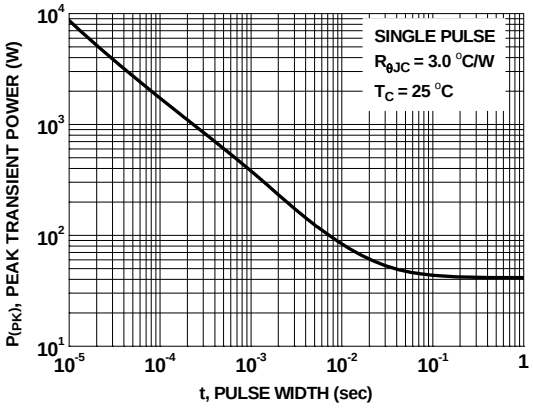



**Figure 25. Single Pulse Maximum Power Dissipation**

## Typical Characteristics (Q2 N-Channel) $T_J$ = 25 °C unless otherwise noted

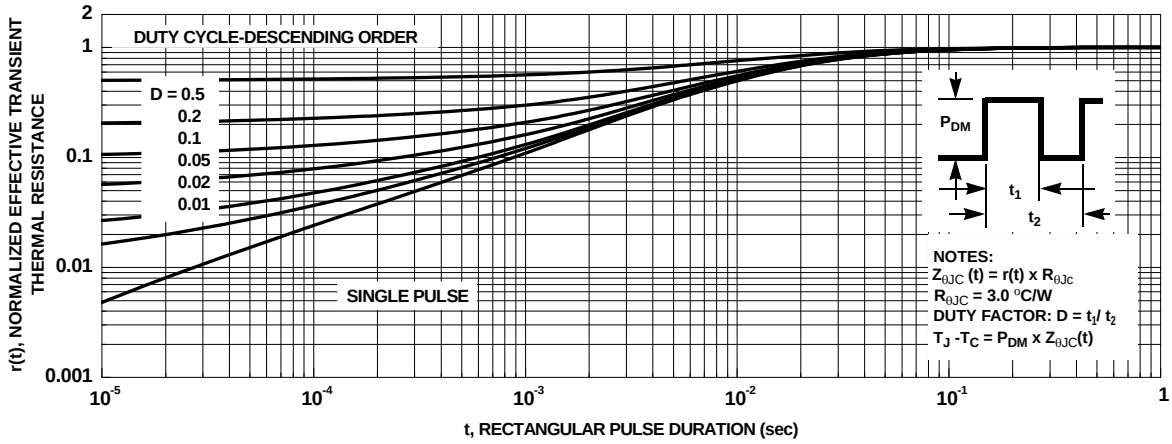



**Figure 26. Junction-to-Case Transient Thermal Response Curve**

## Typical Characteristics (continued)

### SyncFET™ Schottky body diode Characteristics

Fairchild's SyncFET™ process embeds a Schottky diode in parallel with PowerTrench® MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 27 shows the reverses recovery characteristic of the FDPC8014S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

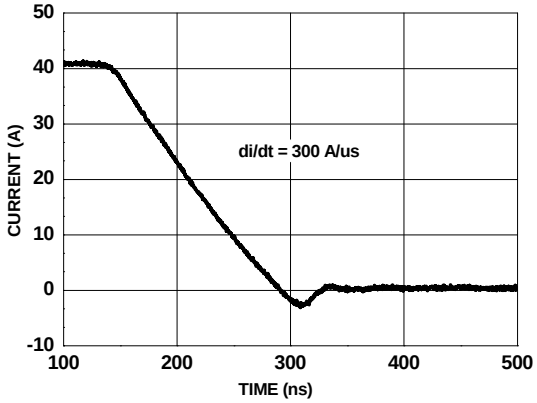



**Figure 27. FDPC8014S SyncFET™ Body Diode Reverse Recovery Characteristic**

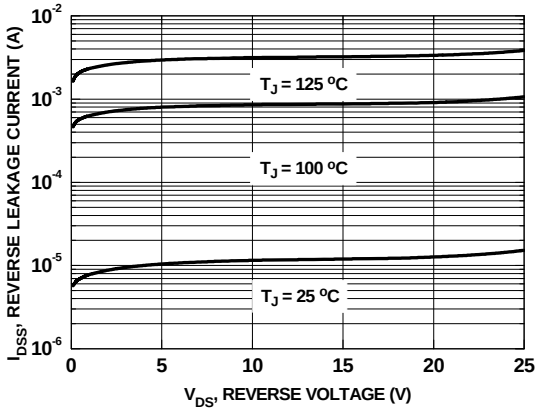
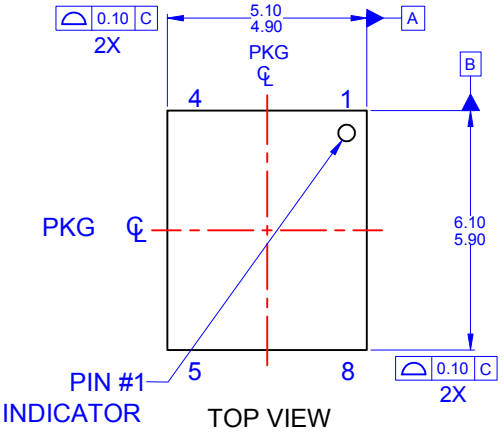
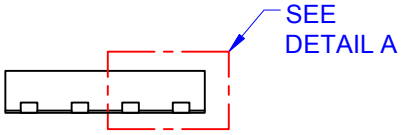


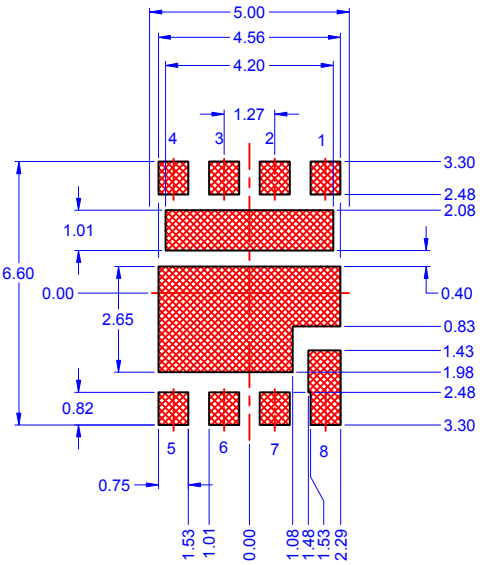

**Figure 28. SyncFET™ Body Diode Reverse Leakage vs. Drain-source Voltage**



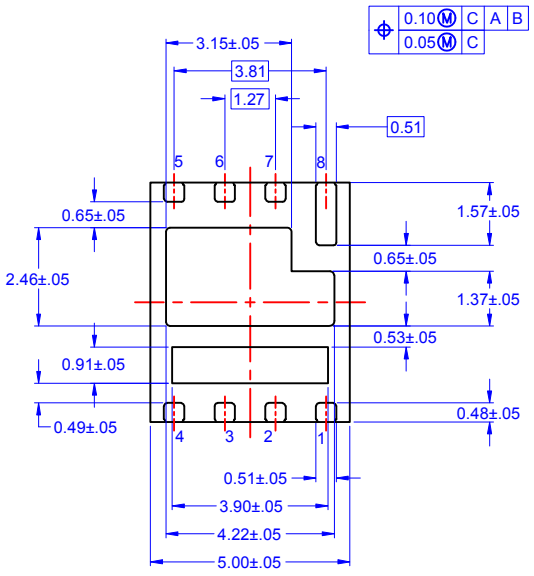

TOP VIEW



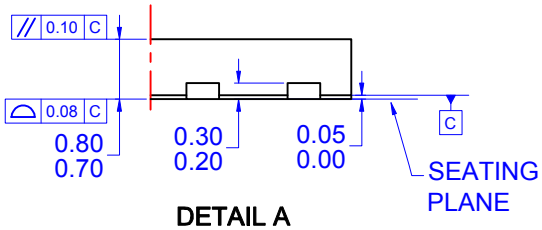

SIDE VIEW




RECOMMENDED LAND PATTERN




BOTTOM VIEW




**DETAIL A**
(SCALE: 2X)

NOTES: UNLESS OTHERWISE SPECIFIED

A) DOES NOT FULLY CONFORM TO JEDEC REGISTRATION, MO-229, DATED 11/2001.
B) ALL DIMENSIONS ARE IN MILLIMETERS.
C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
E) DRAWING FILE NAME: PQFN08KREV2

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